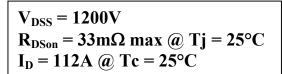
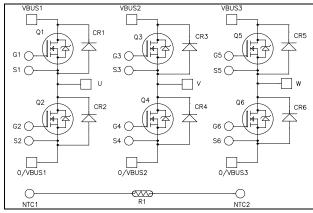


# Triple phase leg SiC MOSFET Power Module





#### VBUS1 VBUS2 VBUS3 **⊕** G1 ● S1 NTC1 0/VBUS2 0/VBUS3 0/VBUS1 ● NTC2 V

### **Application**

- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

#### **Features**

- SiC Power MOSFET
  - High speed switching
  - Low R<sub>DS(on)</sub>
  - Ultra low loss
- SiC Schottky Diode
  - Zero reverse recovery
  - Zero forward recovery
  - Temperature Independent switching behavior
  - Positive temperature coefficient on VF
- Very low stray inductance
- Kelvin source for easy drive
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance

#### **Benefits**

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- **RoHS** Compliant

## All ratings @ $T_j = 25^{\circ}C$ unless otherwise specified

APTSM120TAM33CTPAG-Rev 0 July, 2015

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



#### **Absolute maximum ratings** (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1200	V
T	Continuous Drain Current	$T_c = 25^{\circ}C$	112	
$I_D$	Continuous Diani Current	$T_c = 80$ °C	89	Α
$I_{DM}$	Pulsed Drain current		225	
$V_{GS}$	Gate - Source Voltage		-10/25V	V
$R_{DSon}$	Drain - Source ON Resistance		33	mΩ
$P_{D}$	Power Dissipation	$T_c = 25^{\circ}C$	714	W

## **Electrical Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ , $V_{DS} = 120$		30	300	μΑ	
D	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		27	33	
$R_{DS(on)}$		$I_D = 60A$	$T_j = 175$ °C		46		mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 3mA$		1.7	3		V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				300	nA

# Dynamic Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
C <sub>iss</sub>	Input Capacitance	$V_{GS} = 0V$	$V_{GS} = 0V$		7680		
$C_{oss}$	Output Capacitance	$V_{\rm DS} = 1000V$			360		pF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz	f = 1MHz				
$Q_{g}$	Total gate Charge	$V_{GS} = -5/20V$	$V_{GS} = -5/20V$				
$Q_{\mathrm{gs}}$	Gate – Source Charge	$V_{Bus} = 600V$			120		nC
$Q_{gd}$	Gate – Drain Charge	$I_D = 60A$			120		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching		10			
$T_{r}$	Rise Time	U	$V_{GS} = -5/20V$ ; $V_{Bus} = 800V$				
$T_{d(off)}$	Turn-off Delay Time		$I_D = 60A ; T_J = 150 ^{\circ}C$		45		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 1.7\Omega$			30		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$ $I_D = 60A$ $R_G = 1.7\Omega$	$T_j = 150^{\circ}C$		1.3		mJ
$E_{\text{off}}$	Turn off Energy		$T_j = 150^{\circ}C$		0.7		1113
$R_{Gint}$	Internal gate resistance				1.1		Ω
$R_{\text{thJC}}$	Junction to Case Thermal Resistance	ce				0.21	°C/W

## **Body diode ratings and characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
$V_{SD}$	Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 60A$		3.9		V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 60 \text{A} \; ; \; V_{GS} = -2 \text{V} \ V_{R} = 800 \text{V} \; ; \; di_{F}/dt = 300 \text{A}/\mu \text{s}$		140		ns
Q <sub>rr</sub>	Reverse Recovery Charge			345		nC
$I_{rr}$	Reverse Recovery Current			6		Α

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## SiC schottky diode ratings and characteristics (per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					1200	V
$I_{RRM}$	Reverse Leakage Current	V <sub>R</sub> =1200V	$T_{j} = 25^{\circ}C$ $T_{i} = 175^{\circ}C$		30 1500	600	μΑ
$I_{\mathrm{F}}$	DC Forward Current		$T_j = 1/3$ °C $T_c = 125$ °C		30		A
$V_{\mathrm{F}}$	Diode Forward Voltage	$I_F = 30A$	$T_i = 25^{\circ}C$ $T_i = 175^{\circ}C$		1.5 2.3	1.8	V
Qc	Total Capacitive Charge	$I_F = 30A, V_R = 600V$ $di/dt = 1500A/\mu s$			360		nC
С	Total Capacitance $f = 1MHz, V_R = 200V$			345		рF	
	Total Capacitance	$f = 1MHz, V_R$	= 400V		255		pr.
$R_{thJC}$	Junction to Case Thermal Resistance					0.37	°C/W

#### Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic		Min	Typ	Max	Unit
R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		T <sub>C</sub> =100°C		4		%

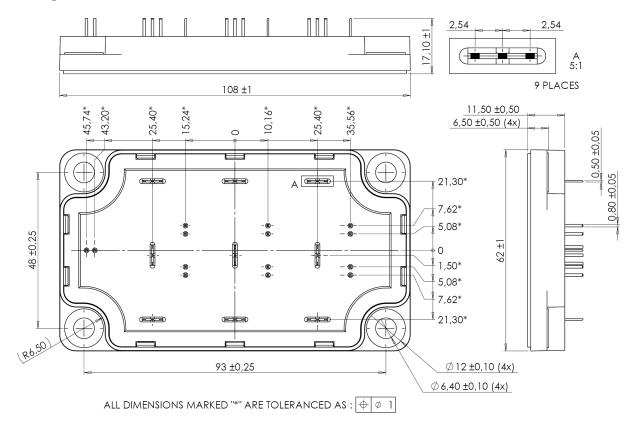
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature R<sub>T</sub>: Thermistor value at T

## Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000		V
$T_{J}$	Operating junction temperature range	rating junction temperature range				
$T_{JOP}$	Recommended junction temperature under switching conditions			-40	T <sub>J</sub> max -25	°C
$T_{STG}$	Storage Temperature Range			-40	125	C
$T_{\rm C}$	Operating Case Temperature			-40	125	
Torque	Mounting torque	To heatsink	M6	3	5	N.m
Wt	Package Weight				250	g



#### Package outline (dimensions in mm)

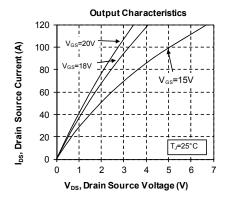


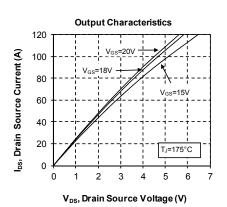
See application note 1902 - Mounting Instructions for SP6-P (12mm) Power Modules on www.microsemi.com

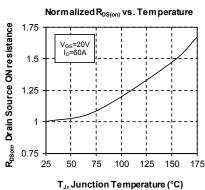
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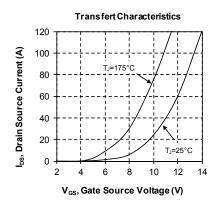


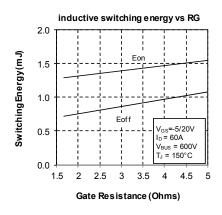
## **Typical SiC MOSFET Performance Curve**

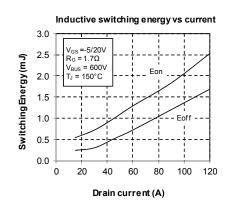


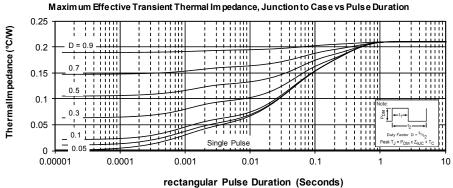




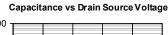


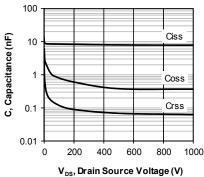




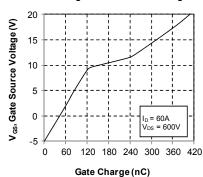




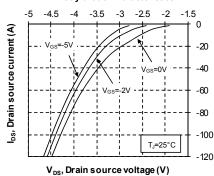




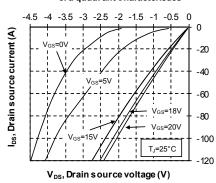
#### Gate Charge vs Gate Source Voltage

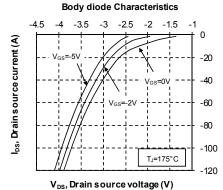


#### **Body diode Characteristics**

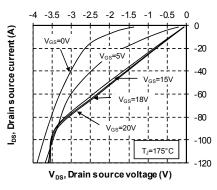


#### 3rd quadrant Characteristics

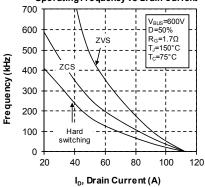




3rd quadrant Characteristics



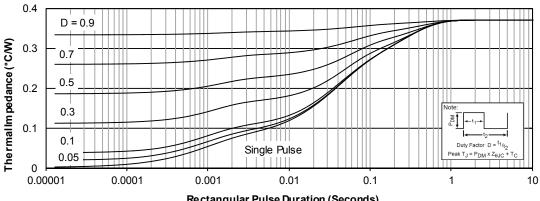
### Operating Frequency vs Drain Current



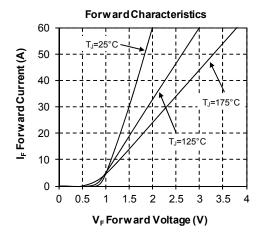


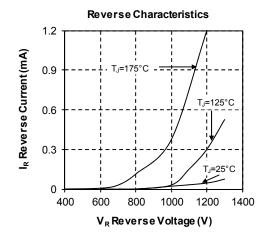
## Typical SiC diode Performance Curve

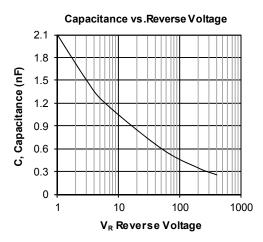
#### Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration



Rectangular Pulse Duration (Seconds)









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